



Docket No.: 220681US0X PCT

ASSISTANT COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

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TECH CENTER 1600/2900

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OBLON
SPIVAK
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NEUSTADT
P.C.

ATTORNEYS AT LAW

RE: Application Serial No.: 10/089,164
Applicants: Patrick CHATON, et al.
Filing Date: March 27, 2002
For: METHOD AND DEVICE FOR DETECTING A
MOLECULAR RECOGNITION REACTION
Group Art Unit:
Examiner:

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SIR:

Attached hereto for filing are the following papers:

Letter

PTO 1449

International Search Report

Cited References (4)

Our check in the amount of \$0.00 is attached covering any required fees. In the event any variance exists between the amount enclosed and the Patent Office charges for filing the above-noted documents, including any fees required under 37 C.F.R. 1.136 for any necessary Extension of Time to make the filing of the attached documents timely, please charge or credit the difference to our Deposit Account No. 15-0030. Further, if these papers are not considered timely filed, then a petition is hereby made under 37 C.F.R. 1.136 for the necessary extension of time. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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MAIER & NEUSTADT, P.C.

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DOCKET NO.: 220681US0XPCT



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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE TECH CENTER 1600/2900

IN RE APPLICATION OF:

: GROUP ART UNIT:

PATRICK CHATON ET AL

:

SERIAL NO.: 10/089,164
(Based on PCT/FR00/02703)

:

EXAMINER:

FILED: MARCH 27, 2002

:

FOR: METHOD AND DEVICE FOR DETECTING A MOLECULAR RECOGNITION
REACTION

LETTER

ASSISTANT COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

SIR:

Applicants would like to make of record the references cited in the International Search Report and PTO Form 1449. Copies of the listed information are attached, where required.

Applicants request that the Examiner consider the references cited in the International Search Report and so indicate by a statement in the first Office Action that the information has been considered.

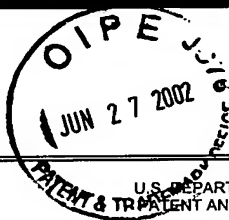
Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,
MAIER & NEUSTADT, P.C.

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Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

220681US0X PCT

SERIAL NO.

10/089,164

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Patrick CHATON, et al.

FILING DATE

March 27, 2002

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,874,213	2/23/99	Cummin et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
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	AM						
	AN						

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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	K. Adelhelm, et al. "DEVELOPMENT OF A SENSITIVE DETECTION SYSTEM BASED ON THE PHOTOTHERMAL EFFECT FOR BIOMOLECULAR INTERACTION STUDIES," Biomedical Optoelectronics In Clinical Chemistry and Biotechnology, September 14, 1995, Vol 2629, Pages 325-333
	AX	Tamao Odake, et al., "HIGH-SPEED SEPARATION USING MINATURIZED SLAB GEL AND HIGH SPATIAL RESOLUTION DETECTION BY THERMAL LENS MICROSCOPE," Proceedings of the 1998 Thermal Therapy, Laser Welding and Tissue Interaction, September 9, 1998, SPIE Vol. 3565, Pages 126-133.
	AY	Takehiko Kitamori, "CHEMISTRY AND ANALYSIS IN INTEGRATED CHEMISTRY LAB ON CHIP," Digest of Papers Nanotechnology, 1999, Pages 70-71
	AZ	

☐ Additional References sheet(s) attached

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.